

Notice of References Cited

Application/Control No.

10/562,152

Applicant(s)/Patent Under
Reexamination
LEE, SUNG-NACK

Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,344,218	02-2002	Dodd et al.	424/605
*	B	US-6,174,521	01-2001	Li et al.	424/65
*	C	US-5,525,331	06-1996	Betts, John A.	424/65
*	D	US-5,770,187	06-1998	Hasebe et al.	424/69
*	E	US-4,898,727	02-1990	Osada et al.	424/76.1
*	F	US-6,096,298	08-2000	Swaile, David Frederick	424/65
*	G	US-6,403,071	06-2002	Scavone et al.	424/65
*	H	US-5,902,572	05-1999	Luebbe et al.	424/66
*	I	US-4,906,454	03-1990	Melanson et al.	424/47
*	J	US-2004/0024055	02-2004	Hahm et al.	514/461
*	K	US-2004/0009244	01-2004	Kim et al.	424/729
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002080335	03-2002	Japan	Sakiguchi - +DWPI Abstr	----
	O	JP 2000079158	03-2000	Japan	Aoki et al - +JPAB Abstr	----
	P	JP 2003081801	03-2003	Japan	Kanehisa - +DWPI Abstr	----
	Q	KR 2002029455	04-2002	Korea	Hwang - DWPI Abstr	----
	R	KR 2002030979	04-2002	Korea	Kim - DWPI Abstr	----
	S	JP 07194683	08-1995	Japan	Hayashi - JPAB Abstr	----
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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